



# FCC PART 90 TYPE APPROVAL EMI MEASUREMENT AND TEST REPORT

For

# Weierwei Electron Science & Technology Co., Ltd.

Room 18F07, New Asia Digital Electronics Plaza,

Xitier Road, Guangzhou, Guangdong, China

FCC ID: YC2VEV-V8

Report Type: **Product Type:** Original Report Walkie Talkie Alvin Huand **Test Engineer:** Alvin Huang **Report Number:** RSZ10041202 **Report Date:** 2010-05-11 Merry Zhao merry, when **Reviewed By:** EMC Engineer **Prepared By:** Bay Area Compliance Laboratories Corp. (Shenzhen) 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China

**Note**: This test report is prepared for the customer shown above and for the device described herein. It may not be duplicated or used in part without prior written consent from Bay Area Compliance Laboratories Corp. This report **must not** be used by the customer to claim product certification, approval, or endorsement by NVLAP\*, NIST, or any agency of the Federal Government. \* This report may contain data that are not covered by the NVLAP accreditation and are marked with an asterisk "\*"

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# Weierwei Electron Science& Technology Co., Ltd.

# FCC ID: YC2VEV-V8

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# **GENERAL INFORMATION**

#### **Product Description for Equipment Under Test (EUT)**

The Weierwei Electron Science & Technology Co., Ltd's product, model number: VEV-V8 (FCC ID: YC2VEV-V8) or the "EUT" as referred to in this report is a Walkie Talkie that operates in the frequency band 400~470 MHz and with two channel spacing of 12.5 kHz (narrow-band)/25 kHz (wide-band). The EUT is measured approximately 3.0 cm L x 5.5 cm W x 10.0 cm H, rated input voltage: DC 7.4V battery.

\* All measurement and test data in this report was gathered from production sample serial number: 1004019 (Assigned by BACL, Shenzhen). The EUT was received on 2010-04-12.

#### **EUT Photo**



Please see additional photos in Exhibit B & C

#### **Objective**

This Type approval report is prepared on behalf of *Weierwei Electron Science & Technology Co., Ltd* in accordance with Part 2, and Part 90 of the Federal Communication Commissions rules.

#### **Related Submittal(s)/Grant(s)**

No related submittal(s).

#### **Test Methodology**

All tests and measurements indicated in this document were performed in accordance with the Code of federal Regulations Title 47 Part 2, Sub-part J as well as the following individual parts:

Part 90 - Private Land Mobile Radio Service

Applicable Standards: TIA 603-C and ANSI 63.4-2003.

All emissions measurement was performed and Bay Area Compliance Laboratories Corp. (Shenzhen). The radiated testing was performed at an antenna-to-EUT distance of 3 meters.

#### **Test Facility**

The Test site used by Bay Area Compliance Laboratories Corp. (Shenzhen) to collect test data is located in the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on November 21, 2007. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2003.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

Additionally, Bay Area Compliance Laboratories Corp. (Shenzhen) is a National Institute of Standards and Technology (NIST) accredited laboratory, under the National Voluntary Laboratory Accredited Program (Lab Code 200707-0).



The current scope of accreditations can be found at http://ts.nist.gov/standards/scopes/2007070.htm.

# **SYSTEM TEST CONFIGURATION**

# **Description of Test Configuration**

The system was configured for testing in a typical fashion (as normally used by a typical user).

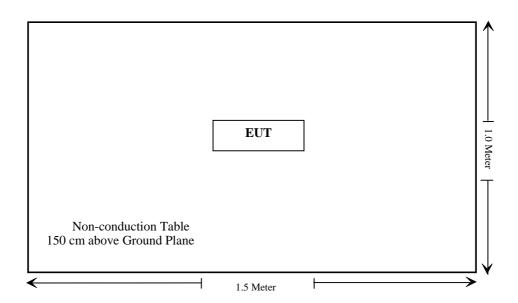
# **Equipment Modifications**

No modifications were made to the unit tested.

# **Configuration of Test Setup**



# **Block Diagram of Test Setup**



# SUMMARY OF TEST RESULTS

FCC Rules	Description of Test	Results
§1.1307(b); §2.1093	RF Exposure	Compliant*
§2.1046; §90.205	RF Output Power	Compliant
§2.1047; §90.207	Modulation Characteristic	Compliant
\$2.1049, \$90.209; \$90.210	Occupied Bandwidth & Emission Mask	Compliant
§2.1051; §90.210	Spurious Emission at Antenna Terminal	Compliant
§2.1053; §90.210	Spurious Radiated Emissions	Compliant
§2.1055; §90.213	Frequency Stability	Compliant
§90.214	Transient Frequency Behavior	Compliant

Note: \* Please refer to the SAR report released by BACL, Report Number: R1005135-SAR.

# FCC §1.1307(b) & §2.1093 - RF EXPOSURE

# **Applicable Standard**

According to FCC §1.1307(b) and §2.1093, protable device operates Part 90 should be subjected to rountine environmental evaluation for RF exposure prior or equipment authorization or use.

Result: Compliance.

Please refer to SAR Report Number: R1005135-SAR.

# FCC §2.1046 & §90.205- RF OUTPUT POWER

#### **Applicable Standard**

FCC §2.1046 and §90.205.

#### **Test Procedure**

1) Conducted RF Output Power

TIA-603-C section 2.2.1

The RF output of the transmitter was connected to the input of the spectrum analyzer through sufficient attenuation.

Spectrum Analyzer setting:

 RBW
 Video B/W

 100 kHz
 300 kHz

2) Radiated Power Output (ERP)

TIA-603-C section 2.2.17

The transmitter was placed on a wooden turntable, and it was transmitting into a non-radiating load, which was also placed on the turntable.

The measurement antenna was placed at a distance of 3 meters from the EUT, during the tests, the antenna height and polarization as well as EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. The test was performed by placing the EUT on 3-orthogonal axis.

The frequency range up to teeth harmonic of the fundamental frequency was investigated.

Remove the EUT and replace it with substitution antenna. A signal generator was connected to the substitution antenna by a non-radiating cable. The absolute levels of the ERP were measured by the substitution.

Absolute level=substituted level+Antenna gain-Cable Loss

#### **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
Sunol Sciences	Broadband Antenna	ЈВ1	A040904-1	2010-03-11	2011-03-11
Sunol Sciences	Bilog Antenna	ЈВ1	A040904-2	2009-05-05	2010-05-05
Rohde&Schwarz	Spectrum Analyzer	FSEM30	849720/019	2009-07-08	2010-07-08
HP	Signal Generator	HP8657A	2849U00982	2009-10-28	2010-10-27

<sup>\*</sup> Statement of Tractability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed per the NVLAP requirements, traceable to NIST.

# **Test Data**

#### **Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	56%
ATM Pressure:	100.1 kPa

The testing was performed by Alvin Huang on 2010-05-01.

Test Mode: Transmitting

Test Result: Please refer to following table and plots.

# 1) Conducted Output Power:

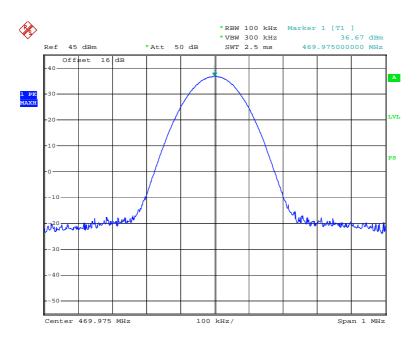
Frequency Spacing (kHz)	Frequency (MHz)	Output Power (dBm)	Output Power (Watt)	Rated Output Power (Watt)	Comment
		High ou	tput power		
	400.025	36.71	4.69	5	Low CH
25.0	435.000	36.70	4.68	5	Middle CH
	469.975	36.66	4.63	5	High CH
	400.025	36.71	4.69	5	Low CH
12.5	435.000	36.69	4.67	5	Middle CH
	469.975	36.67	4.65	5	High CH
		Middle o	utput power		
	400.025	32.61	1.82	2	Low CH
25.0	435.000	33.43	2.20	2	Middle CH
	469.975	33.98	2.50	2	High CH
	400.025	32.64	1.84	2	Low CH
12.5	435.000	33.41	2.19	2	Middle CH
	469.975	33.98	2.50	2	High CH
		Low ou	tput power		
	400.025	29.06	0.81	1	Low CH
25.0	435.000	30.13	1.03	1	Middle CH
	469.975	31.11	1.29	1	High CH
	400.025	29.13	0.82	1	Low CH
12.5	435.000	30.26	1.06	1	Middle CH
	469.975	31.10	1.29	1	High CH

# Effective Radiated Power (ERP)

Indic	ated	Table	Test An	tenna		:	Substitu	ted		Absolute	Output
Freq. (MHz)	S.A. Amp. (dBµV)	Angle Degree	Height (m)	Polar (H/V)	Freq. (MHz)	Level (dBm)	Polar (H/V)	Antenna Gain Cord.	Cable Loss ( dB)	Level ( dBm)	Output Power (Watt)
				12	.5 kHz C	hannel	Spacing				
400.025	116.89	176	1.3	Н	400.025	36.1	Н	0	0.7	35.4	3.47
430.000	116.67	354	1.5	Н	430.000	36.1	Н	0	0.7	35.4	3.47
469.975	116.74	0	1.6	Н	469.975	36.3	Н	0	0.7	35.6	3.63
400.025	117.34	360	1.7	V	400.025	36.7	V	0	0.7	36.0	3.98
469.975	117.46	28	1.7	V	469.975	36.8	V	0	0.7	36.1	4.07
430.000	117.64	156	1.6	V	430.000	37.0	V	0	0.7	36.3	4.27
				25	.0 kHz C	hannel	Spacing				
400.025	116.53	56	1.6	Н	400.025	35.9	Н	0	0.7	35.2	3.31
469.975	116.59	160	1.6	Н	469.975	36.1	Н	0	0.7	35.4	3.47
430.000	116.76	81	1.5	Н	430.000	36.2	Н	0	0.7	35.5	3.55
469.975	117.12	172	1.7	V	469.975	36.5	V	0	0.7	35.8	3.80
400.025	117.27	156	1.7	V	400.025	36.6	V	0	0.7	35.9	3.89
430.000	117.59	360	1.2	V	430.000	36.9	V	0	0.7	36.2	4.17

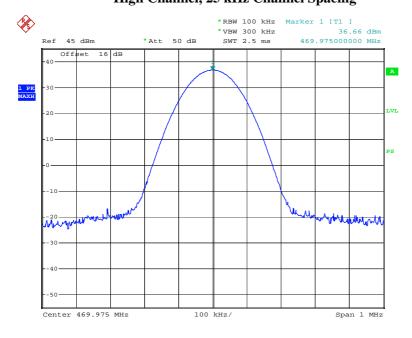
#### **Antenna Port Conducted Output Power:**

# High Channel, 12.5 kHz Channel Spacing



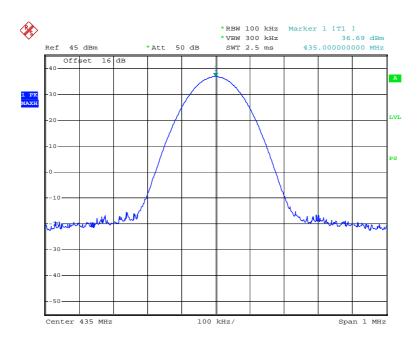
Date: 1.MAY.2010 08:57:35

# High Channel, 25 kHz Channel Spacing



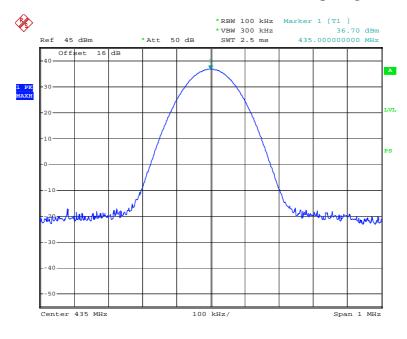
Date: 1.MAY.2010 08:57:13

# Middle Channel, 12.5 kHz Channel Spacing



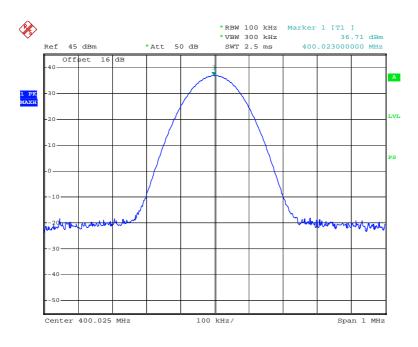
Date: 1.MAY.2010 08:58:07

# Middle Channel, 25 kHz Channel Spacing



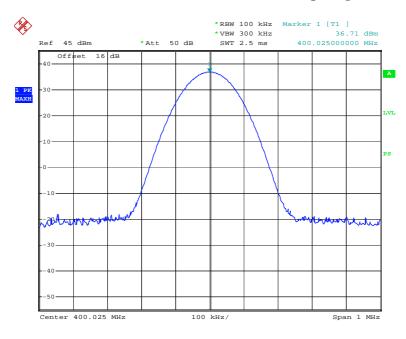
Date: 1.MAY.2010 08:56:49

# Low Channel, 12.5 kHz Channel Spacing



Date: 1.MAY.2010 08:58:36

# Low Channel, 25 kHz Channel Spacing



Date: 1.MAY.2010 08:52:42

# FCC §2.1047 & §90.207 - MODULATION CHARACTERISTIC

#### **Applicable Standard**

FCC §2.1047 & §90.207:

- (a) Equipment which utilizes voice modulated communication shall show the frequency response of the audio modulating circuit over a range of 100 to 5000 Hz. for equipment which is required to have a low pass filter, the frequency response of the filter, or all of the circuitry installed between the modulation limited and the modulated stage shall be supplied.
- (b) Equipment which employs modulation limiting, a curve showing the percentage of modulation versus the modulation input voltage shall be supplied.

#### **Test Procedure**

TIA/EIA-603 2.2.3

#### **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
HP	Modulation Analyzer	8901B	3438A05208	2010-03-03	2011-03-02
NANYAN	Audio Generator	NY2201	019829	2009-12-23	2010-12-23

<sup>\*</sup> Statement of Traceability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

#### **Test Data**

#### **Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	56%
ATM Pressure:	100.1 kPa

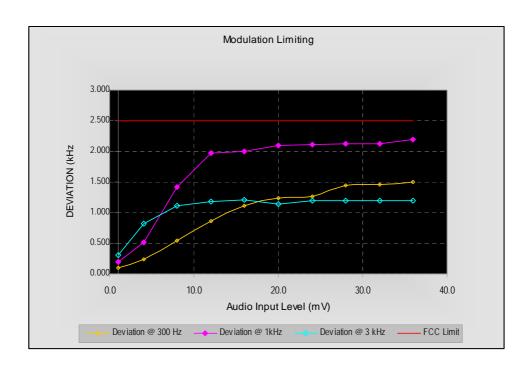
The testing was performed by Alvin Huang on 2010-05-08.

Test Mode: Transmitting

**Modulation Limiting** 

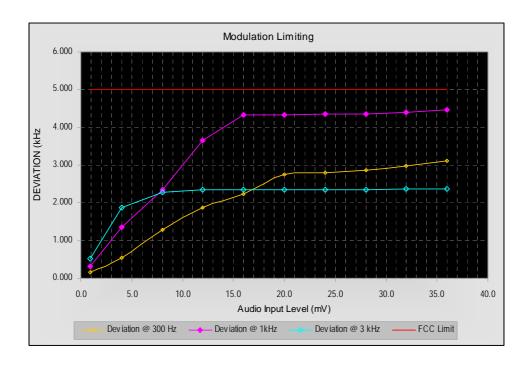
Carrier Frequency: 435.00 MHz, Channel Separation=12.5 kHz

Audio Input	Freq	Frequency Deviation (kHz)				
Level [mV]	@ 300 Hz	@ 1kHz	@ 3 kHz	FCC Limit [kHz]		
1.0	0.100	0.200	0.301	2.5		
4.0	0.235	0.512	0.815	2.5		
8.0	0.536	1.412	1.106	2.5		
12.0	0.867	1.975	1.186	2.5		
16.0	1.111	2.006	1.205	2.5		
20.0	1.243	2.101	1.134	2.5		
24.0	1.267	2.109	1.197	2.5		
28.0	1.450	2.125	1.197	2.5		
32.0	1.458	2.129	1.198	2.5		
36.0	1.501	2.200	1.197	2.5		



Carrier Frequency: 435.00 MHz, Channel Separation=25.0 kHz

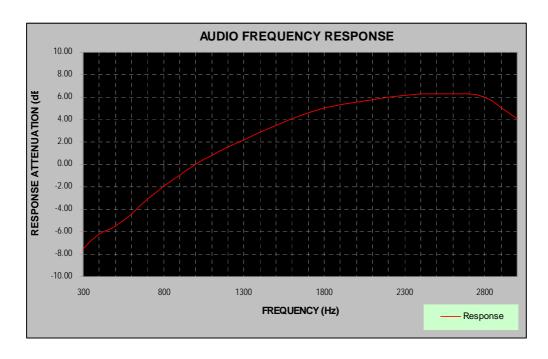
Audio Input	Freq	Frequency Deviation (kHz)					
Level [mV]	@ 300 Hz	@ 1kHz	@ 3 kHz	[kHz]			
1.0	0.167	0.325	0.517	5.0			
4.0	0.534	1.346	1.867	5.0			
8.0	1.286	2.342	2.267	5.0			
12.0	1.867	3.654	2.339	5.0			
16.0	2.231	4.325	2.355	5.0			
20.0	2.762	4.334	2.356	5.0			
24.0	2.798	4.345	2.357	5.0			
28.0	2.875	4.359	2.355	5.0			
32.0	2.967	4.405	2.358	5.0			
36.0	3.105	4.467	2.359	5.0			



**Audio Frequency Response** 

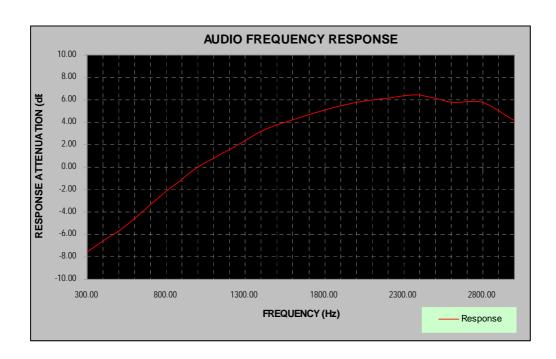
Carrier Frequency: 435.00 MHz, Channel Separation=12.5 kHz

Audio Frequency (Hz)	Response Attenuation (dB)
300	-7.54
400	-6.20
500	-5.51
600	-4.44
700	-3.10
800	-1.94
900	-0.93
1000	0.00
1200	1.58
1400	2.92
1600	4.08
1800	5.01
2000	5.58
2200	6.02
2400	6.28
2600	6.28
2800	6.02
3000	4.08



Carrier Frequency: 435.00 MHz, Channel Separation=25.0 kHz

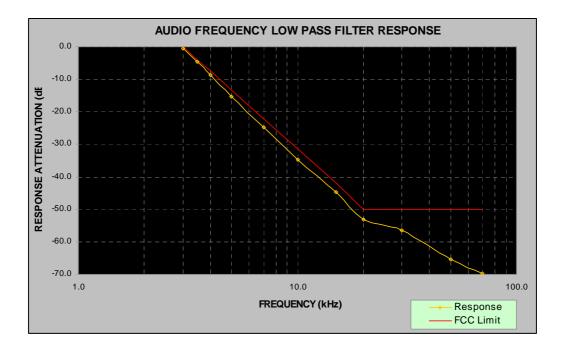
Audio Frequency (Hz)	Response Attenuation (dB)
300	-7.54
400	-6.56
500	-5.68
600	-4.58
700	-3.35
800	-2.16
900	-1.11
1000	0.00
1200	1.58
1400	3.17
1600	4.19
1800	5.11
2000	5.80
2200	6.15
2400	6.44
2600	5.81
2800	5.80
3000	4.14



# **Audio Frequency Low Pass Filter Response**

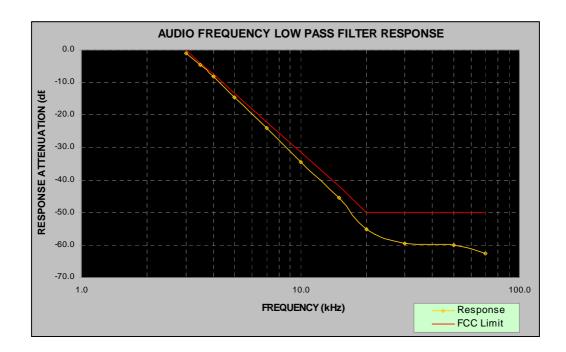
Carrier Frequency: 435.00 MHz, Channel Separation=12.5 kHz

Audio Frequency (kHz)	Response Attenuation (dB)	FCC Limit (dB)
3.0	-0.5	0.0
3.5	-4.5	-4.0
4.0	-8.7	-7.5
5.0	-15.4	-13.3
7.0	-24.7	-22.1
10.0	-34.8	-31.4
15.0	-44.6	-42.0
20.0	-53.2	-50.0
30.0	-56.5	-50.0
50.0	-65.5	-50.0
70.0	-69.8	-50.0



Carrier Frequency: 435.00 MHz, Channel Separation=25.0 kHz

Audio Frequency (kHz)	Response Attenuation (dB)	FCC Limit (dB)
3.0	-0.9	0.0
3.5	-4.6	-4.0
4.0	-8.1	-7.5
5.0	-14.5	-13.3
7.0	-24.1	-22.1
10.0	-34.4	-31.4
15.0	-45.5	-42.0
20.0	-55.1	-50.0
30.0	-59.5	-50.0
50.0	-60.1	-50.0
70.0	-62.7	-50.0



# FCC §2.1049, §90.209 & §90.210 – OCCUPIED BANDWIDTH & EMISSION MASK

#### **Applicable Standard**

FCC §2.1049, §90.209 and §90.210

Emission Mask D—12.5 kHz channel bandwidth equipment. For transmitters designed to operate with a 12.5 kHz channel bandwidth, any emission must be attenuated below the power (P) of the highest emission contained within the authorized bandwidth as follows:

- 1) For any frequency removed from the center of the authorized bandwidth  $f_0$  to 5.625 KHz removed from  $f_0$ , 0dB.
- 2) On any frequency removed from the center of the authorized bandwidth by a displacement frequency ( $f_d$  in kHz) of more than 5.626kHz but no more than 12.5kHz, at least 7.27 ( $f_d$  –2.88kHz) dB.
- 3) On any frequency removed from the center of the authorized bandwidth by a displacement frequency ( $f_d$  in kHz) of more than 12.5kHz at least:

Emission Mask B. For transmitters that are equipped with an audio low-pass filter, the power of any emission must be attenuated below the unmodulated carrier power (P) as follows:

- 1) For any frequency removed from the center of the assigned channel by more than 50 percent up to and including 100 percent of the authorized bandwidth, at least 25 dB.
- 2) On any frequency removed from the center of the assigned channel by more than 100 percent up to and including 250 percent, at least 35 dB.
- 3) On any frequency removed from the center of the assigned channel by more than 250 percent at least:

The resolution bandwidth was 300Hz or greater for measuring up to 250kHz from the edge of the authorized frequency segment, and 30kHz or greater for measuring more than 250kHz from the authorized frequency segment.

#### **Test Procedure**

The RF output of the transmitter was connected to the input of the spectrum analyzer through sufficient attenuation.

The resolution bandwidth of the spectrum analyzer was set at 300 Hz and the spectrum was recorded in the frequency band  $\pm 50$  kHz from the carrier frequency.



# **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
Rohde & Schwarz	EMI Test Receiver	ESCI	100035	2009-11-24	2010-11-24
НР	Modulation Analyzer	8901B	3438A05208	2010-03-03	2011-03-02
NANYAN	Audio Generator	NY2201	019829	2009-12-23	2010-12-23

<sup>\*</sup> Statement of Traceability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

#### **Test Data**

#### **Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	56%
ATM Pressure:	100.1 kPa

The testing was performed by Alvin Huang on 2010-05-02.

#### **Emission Designator**

According to FCC §2.201 & §2.202, Bn=2M + 2DK

1) 435 MHz, Channel spacing =12.5 kHz

$$Bn=2M + 2DK$$

Where 
$$M = 3000$$
,  $D = 2500$  kHz,  $K = 1$ 

Bn = 
$$2*(3000) + 2*(2500) = 11 \text{ kHz}$$

Emission Designator: 11K0F3E

2) 435 MHz, Channel spacing =25 kHz

$$Bn=2M + 2DK$$

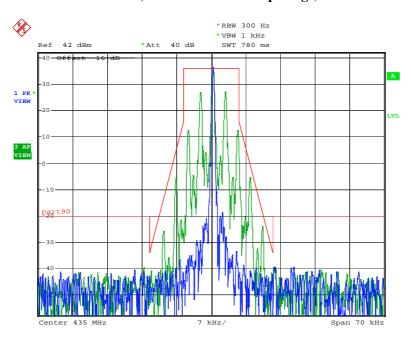
Where 
$$M = 3000$$
,  $D = 5000$  kHz,  $K = 1$ 

Bn = 
$$2*(3000) + 2*(5000) = 16 \text{ kHz}$$

Emission Designator: 16K0F3E

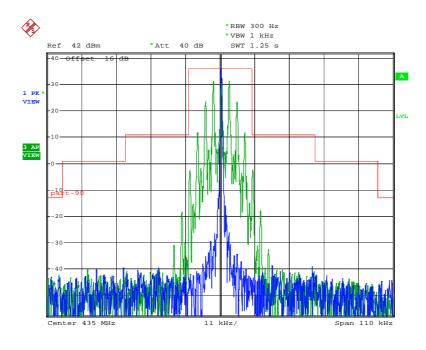
Please refer to the emission mask hereinafter plots.

Emission Mask D, 12.5 kHz Channel Spacing (Middle Channel)



Date: 2.MAY.2010 01:47:20

# Emission Mask B, 25.0 kHz Channel Spacing (Middle Channel)



Date: 2.MAY.2010 01:49:48

# FCC §2.1051 & §90.210 - SPURIOUS EMISSIONS AT ANTENNA TERMINALS

#### **Applicable Standard**

Emission Mask D—12.5 kHz channel bandwidth equipment. For transmitters designed to operate with a 12.5 kHz channel bandwidth, any emission must be attenuated below the power (P) of the highest emission contained within the authorized bandwidth as follows:

- 1) For any frequency removed from the center of the authorized bandwidth  $f_0$  to 5.625 kHz removed from  $f_0$ , 0 dB.
- 2) On any frequency removed from the center of the authorized bandwidth by a displacement frequency ( $f_d$  in kHz) of more than 5.626 kHz but no more than 12.5 kHz, at least 7.27 ( $f_d$  –2.88 kHz) dB.
- 3) On any frequency removed from the center of the authorized bandwidth by a displacement frequency ( $f_d$  in kHz) of more than 12.5 kHz at least:

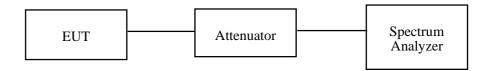
Emission Mask B. For transmitters that are equipped with an audio low-pass filter, the power of any emission must be attenuated below the unmodulated carrier power (P) as follows:

- 1) For any frequency removed from the center of the assigned channel by more than 50 percent up to and including 100 percent of the authorized bandwidth, at least 25 dB.
- 2) On any frequency removed from the center of the assigned channel by more than 100 percent up to and including 250 percent, at least 35 dB.
- 3) On any frequency removed from the center of the assigned channel by more than 250 percent at least:

The resolution bandwidth was 300 Hz or greater for measuring up to 250 kHz from the edge of the authorized frequency segment, and 30 kHz or greater for measuring more than 250 kHz from the authorized frequency segment.

#### **Test Procedure**

The RF output of the Walkie Talkie was connected to a spectrum analyzer through appropriate attenuation. The resolution bandwidth of the spectrum analyzer was set at 100 kHz. Sufficient scans were taken to show any out of band emissions up to 10<sup>th</sup> harmonic.



# **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
Rohde & Schwarz	Spectrum Analyzer	FSEM30	849720/019	2009-07-08	2010-07-08
Rohde & Schwarz	EMI Test Receiver	ESCI	100035	2009-11-24	2010-11-23

<sup>\*</sup> Statement of Traceability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

#### **Test Data**

#### **Environmental Conditions**

Temperature:	25 °C
<b>Relative Humidity:</b>	56%
ATM Pressure:	100.1 kPa

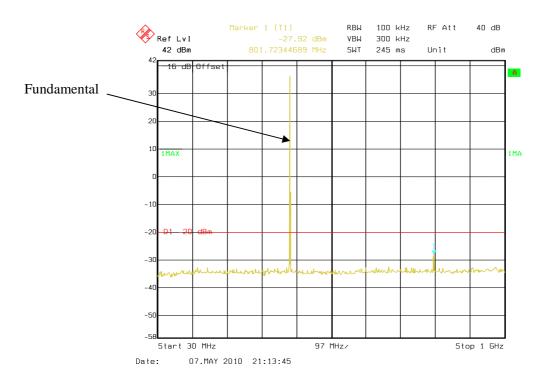
The testing was performed by Alvin Huang on 2010-05-07.

Please refer to the following plots.

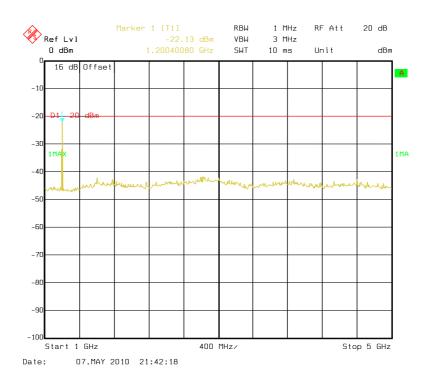
Test Mode: Transmitting

# 12.5 kHz Channel Spacing, Low Channel

#### 30 MHz - 1 GHz

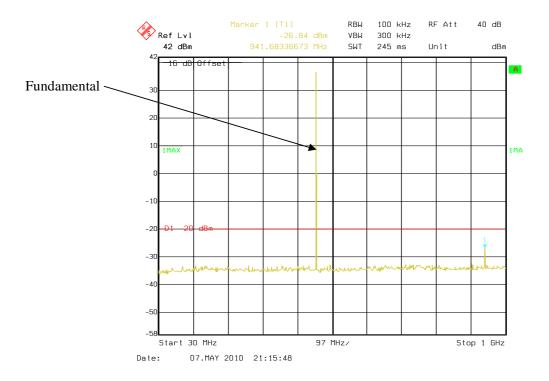


### 1 - 5 GHz

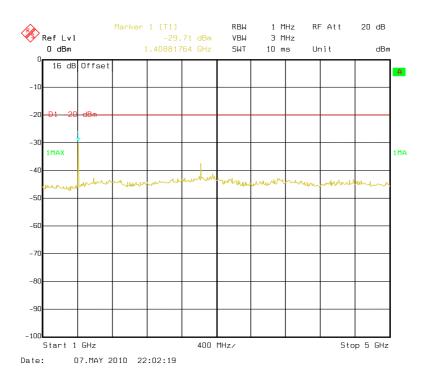


# 12.5 kHz Channel Spacing, High Channel

#### 30 MHz - 1 GHz

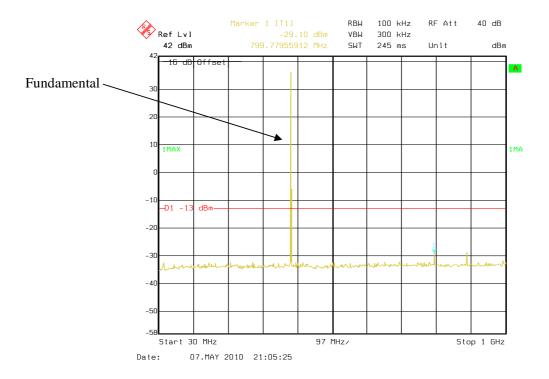


### 1 – 5 GHz

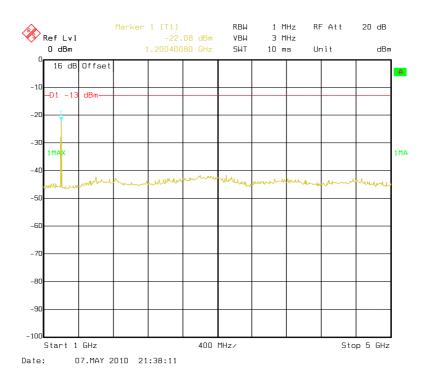


# 25 kHz Channel Spacing, Low Channel

#### 30 MHz - 1 GHz

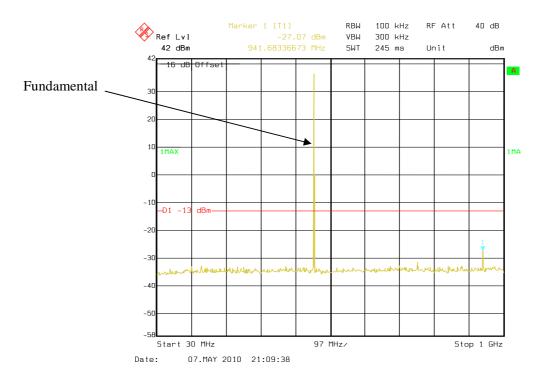


### 1 – 5 GHz

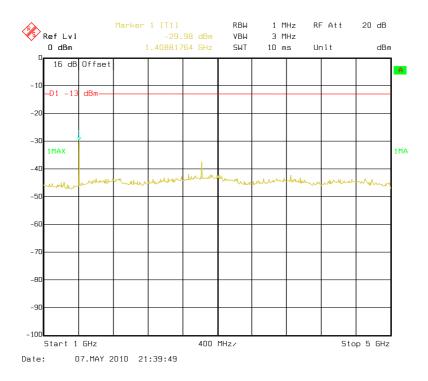


# 25 kHz Channel Spacing, High Channel

#### 30 MHz - 1 GHz



### 1 – 5 GHz



# FCC §2.1053 & §90.210 - RADIATED SPURIOUS EMISSIONS

#### **Applicable Standard**

FCC §2.1053 and §90.210

#### **Test Procedure**

The transmitter was placed on a wooden turntable, and it was transmitting into a non-radiating load, which was also placed on the turntable.

The measurement antenna was placed at a distance of 3 meters from the EUT. During the tests, the antenna height and polarization as well as EUT azimuth were varied in order to identify the maximum level of emissions from the EUT. The test was performed by placing the EUT on 3-orthogonal axis.

The frequency range up to teeth harmonic of the fundamental frequency was investigated.

Remove the EUT and replace it with substitution antenna. A signal generator was connected to the substitution antenna by a non-radiating cable. The absolute levels of the spurious emissions were measured by the substitution.

Spurious emissions in dB =10 1g (TXpwr in Watts/0.001)-the absolute level

Spurious attenuation limit in dB = $43+10 \text{ Log}_{10}$  (power out in Watts) Spurious attenuation limit in dB = $50+10 \text{ Log}_{10}$  (power out in Watts) for EUT with a 12.5 kHz channel bandwidth.

#### **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
Sunol Sciences	Horn Antenna	DRH-118	A052604	2010-05-05	2011-05-04
Sunol Sciences	Broadband Antenna	JB1	A040904-1	2010-03-11	2011-03-11
Sunol Sciences	Bilog Antenna	JB1	A040904-2	2009-05-05	2010-05-04
Rohde & Schwarz	Spectrum Analyzer	FSEM30	849720/019	2009-07-08	2010-07-08
HP	Signal Generator	HP8657A	2849U00982	2009-10-28	2010-10-27
A.H. System	Horn Antenna	SAS-200/571	135	2009-05-17	2010-05-17
HP	Synthesized Sweeper	8341B	2624A00116	2010-03-03	2011-03-02

<sup>\*</sup> Statement of Traceability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

#### **Test Results Summary**

**7.6 dB** at **2400.15 MHz** in the **Vertical** polarization (Low Channel, 12.5 kHz) **12.2 dB** at **2819.85 MHz** in the **Vertical** polarization (High Channel, 12.5 kHz) **15.6 dB** at **2400.15 MHz** in the **Vertical** polarization (Low Channel, 25 kHz) **18.3 dB** at **2819.85 MHz** in the **Vertical** polarization (High Channel, 25 kHz)

# **Test Data**

# **Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	56%
ATM Pressure:	100.1 kPa

The testing was performed by Alvin Huang on 2010-05-01.

Indi	cated	Table	Test A	ıtenna		S	ubstitut	ted		Absolute	FCC	Part 90
Freq. (MHz)	S.A. Amp. (dBµV/m)	Angle (Degree)	Height (m)	Polar (H/V)	Freq. (MHz)	Level (dBm)	Ant. Polar (H/V)	Ant. Gain Cord. (dB)	Cable Loss (dB)	Level (dBm)	Limit (dBm)	Margin (dB)
		Low	Channe	l, f=400	0.025 MH	z (12.5	kHz C	hannel Spa	cing)			
2400.15	62.18	284	1.12	V	2400.15	-33.8	V	7.4	1.2	-27.6	-20	7.6
2400.15	57.28	360	1.97	Н	2400.15	-42.7	Н	7.4	1.2	-36.5	-20	16.5
1200.075	53.25	167	1.25	V	1200.075	-47.8	V	6.3	0.8	-42.3	-20	22.3
1200.075	47.52	76	1.36	Н	1200.075	-49.7	Н	6.3	0.8	-44.2	-20	24.2
800.05	41.00	256	1.16	V	800.05	-54.3	V	0	0.7	-55.0	-20	35.0
800.05	36.79	164	1.98	Н	800.05	-58.3	Н	0	0.7	-59.0	-20	39.0
		High	Channel	, f= 46	9.975 MF	Iz (12.5	5 kHz (	Channel Spa	cing)			
2819.85	57.94	146	1.35	V	2819.85	-38.2	V	7.3	1.3	-32.2	-20	12.2
1409.925	56.35	169	1.32	V	1409.925	-44.6	V	6.4	0.9	-39.1	-20	19.1
939.95	54.66	95	1.32	V	939.95	-40.2	V	0	0.7	-40.9	-20	20.9
2819.85	52.03	176	1.76	Н	2819.85	-48.0	Н	7.3	1.3	-42.0	-20	22.0
939.95	52.48	247	1.13	Н	939.95	-42.1	Н	0	0.7	-42.8	-20	22.8
1879.9	46.15	175	1.12	V	1879.9	-49.8	V	6.1	1.0	-44.7	-20	24.7
1409.925	46.10	165	1.97	Н	1409.925	-52.8	Н	6.4	0.9	-47.3	-20	27.3
2349.875	43.56	125	1.86	Н	2349.875	-57.3	Н	7.4	1.2	-51.1	-20	31.1
		Low	Channe	el, f=40	00.025 MI	Iz (25)	kHz Cł	nannel Spac	ing)			
2400.15	61.29	102	1.26	V	2400.15	-34.8	V	7.4	1.2	-28.6	-13	15.6
2800.175	54.79	175	1.75	Н	2800.175	-45.2	Н	7.3	1.3	-39.2	-13	26.2
1200.075	53.26	105	1.65	V	1200.075	-47.8	V	6.3	0.8	-42.3	-13	29.3
1200.075	47.13	91	1.97	Н	1200.075	-50.1	Н	6.3	0.8	-44.6	-13	31.6
1600.1	49.56	186	1.46	V	1600.1	-50.5	V	6.2	1.0	-45.3	-13	32.3
2400.15	46.98	198	1.86	Н	2400.15	-53.2	Н	7.4	1.2	-47.0	-13	34.0
800.05	41.84	346	1.30	V	800.05	-53.5	V	0	0.7	-54.2	-13	41.2
800.05	37.79	125	1.65	Н	800.05	-57.3	Н	0	0.7	-58.0	-13	45.0
		High	Channe	el, f=4	69.975 M	Hz (25	kHz C	hannel Spac	cing)			
2819.85	58.76	355	1.44	V	2819.85	-37.3	V	7.3	1.3	-31.3	-13	18.3
1409.925	56.97	206	1.45	V	1409.925	-44.1	V	6.4	0.9	-38.6	-13	25.6
939.95	55.04	312	1.35	V	939.95	-39.8	V	0	0.7	-40.5	-13	27.5
939.95	53.47	50	1.96	Н	939.95	-41.0	Н	0	0.7	-41.7	-13	28.7
2819.85	51.33	178	1.85	Н	2819.85	-48.7	Н	7.3	1.3	-42.7	-13	29.7
1879.9	47.16	360	1.35	V	1879.9	-48.8	V	6.1	1.0	-43.7	-13	30.7
1409.925	47.15	16	1.67	Н	1409.925	-51.8	Н	6.4	0.9	-46.3	-13	33.3
2349.875	43.75	196	1.86	Н	2349.875	-57.1	Н	7.4	1.2	-50.9	-13	37.9

# FCC §2.1055 & §90.213- FREQUENCY STABILITY

#### **Applicable Standard**

FCC §2.1055& §90.213

#### **Test Procedure**

Frequency Stability vs. Temperature: The equipment under test was connected to an external DC power supply and the RF output was connected to an f Spectrum Analyzer via feed-through attenuators. The EUT was placed inside the temperature chamber. The DC leads and RF output cable exited the chamber through an opening made for the purpose.

After the temperature stabilized for approximately 20 minutes, the frequency output was recorded from the counter.

The frequency stability shall be measured with variation of primary supply voltage as follows:

(1) Vary primary supply voltage from 85 to 115 percent of the nominal value for other than hand carried battery equipment.

# **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
WUHUAN	Temperature & Humidity Chamber	HTP205	20021115	2009-05-09	2010-05-09
Hewlett-Packard	Frequency Counter	5342A	2317A08289	2010-04-22	2011-04-22

<sup>\*</sup> Statement of Traceability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

#### **Test Data**

#### **Environmental Conditions**

Temperature:	25 °C
Relative Humidity:	56%
ATM Pressure:	100.1 kPa

The testing was performed by Alvin Huang on 2010-05-07.

Test Mode: Transmitting

# 1) 12.5 kHz Channel Spacing

Reference Frequency: 435.00 MHz, Limit: 2.5 ppm					
Test Environment		Frequency Measure with Time Elapsed			
Temperature (°C)	Power Supplied (Vdc)	Measured Frequency (MHz)	Frequency Error (ppm)		
Frequency Stability versus Input Temperature					
50	7.4	435.000381	0.875862		
40	7.4	435.000378	0.868966		
30	7.4	435.000382	0.878161		
20	7.4	435.000388	0.891954		
10	7.4	435.000380	0.873563		
0	7.4	435.000381	0.875862		
-10	7.4	435.000379	0.871264		
-20	7.4	435.000386	0.887356		
-30	7.4	435.000384	0.882759		
Frequency Stability versus Input Voltage					
25	6.5	435.000384	0.882759		

# 2) 25 kHz Channel Spacing

	Reference Frequency: 435.00 MHz, Limit: 5 ppm				
Test Env	Test Environment		Frequency Measure with Time Elapsed		
Temperature (°C)	Power Supplied (Vdc)	Measured Frequency (MHz)	Frequency Error (ppm)		
Frequency Stability versus Input Temperature					
50	7.4	435.000385	0.885057		
40	7.4	435.000381	0.875862		
30	7.4	435.000386	0.887356		
20	7.4	435.000387	0.889655		
10	7.4	435.000379	0.871264		
0	7.4	435.000386	0.887356		
-10	7.4	435.000379	0.871264		
-20	7.4	435.000386	0.887356		
-30	7.4	435.000381	0.875862		
	Frequency Stabil	ity versus Input Voltag	ge		
25	6.5	435.000384	0.882759		

# FCC §90.214 - TRANSIENT FREQUENCY BEHAVIOR

# **Applicable Standard**

FCC §90.214

#### **Test Procedure**

TIA/EIA-603 2.2.19

# **Test Equipment List and Details**

Manufacturer	Description	Model No.	Serial No.	Calibration Date	Calibration Due Date
TEKTRONIX	Digital Phosphor Oscilloscope	TDS 7104	B020518	2010-03-03	2011-03-02
HP	Modulation Analyzer	8901B	3438A05208	2010-03-03	2011-03-02
НР	Signal Generator	HP8657A	2849U00982	2009-10-28	2010-10-27

<sup>\*</sup> Statement of Traceability: Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

#### **Test Data**

#### **Environmental Conditions**

Temperature:	25 °C	
<b>Relative Humidity:</b>	56%	
ATM Pressure:	100.1 kPa	

The testing was performed by Alvin Huang on 2010-05-08.

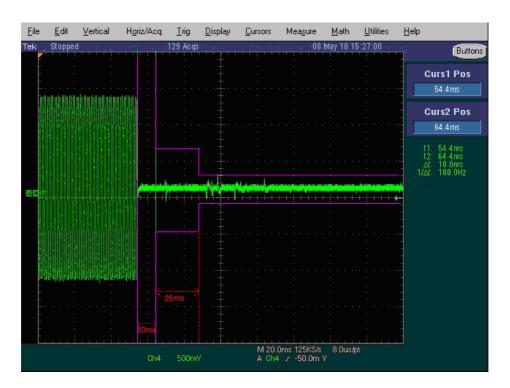
Test Mode: Transmitting

# For 12.5 kHz Channel Spacing:

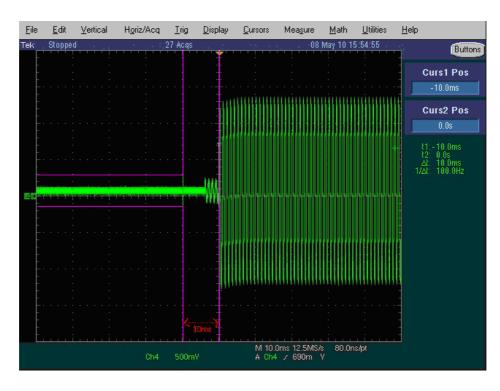
Channel Separation (kHz)	Operation Frequency (MHz)	Transient Period (ms)	Transient Frequency	Result	
12.5	435.00	< 10	+/-12.5 kHz		
		< 25	+/-6.25 kHz	Pass	
		< 10	+/-12.5 kHz		
25.0	435.00	< 10	+/-25.0 kHz		
		25.0 435.00	< 25	+/-12.5 kHz	Pass
		< 10	+/-25.0kHz		

Please refer to the following plots.

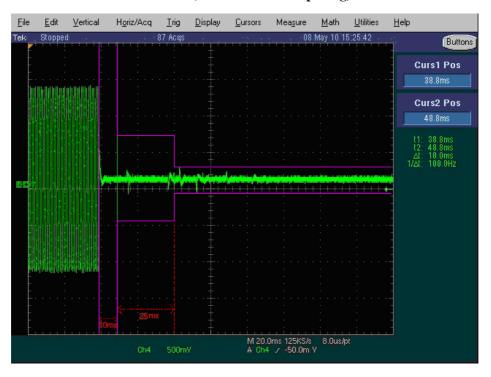
# Turn on (12.5 kHz Channel Spacing)



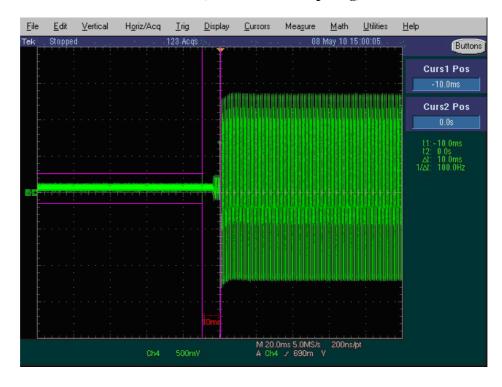
**Turn off (12.5 kHz Cahnnel Spacing)** 



Turn on (25 kHz Channel Spacing)



**Turn off (25 kHz Channel Spacing)** 



\*\*\*\*\* End of Report \*\*\*\*\*